

## N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
BUZ353	500 V	0.6 Ω	9.5 A

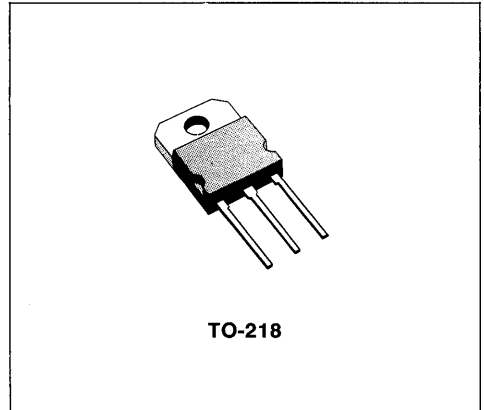
- HIGH SPEED SWITCHING
- HIGH VOLTAGE - 500V FOR OFF-LINE SMPS
- HIGH CURRENT - 9.5A FOR UP TO 250W SMPS
- ULTRA FAST SWITCHING FOR OPERATION AT < 100KHz
- EASY DRIVE FOR REDUCED COST AND SIZE

### INDUSTRIAL APPLICATIONS:

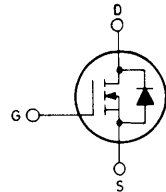
- SWITCHING POWER SUPPLIES
- MOTOR CONTROLS

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and very fast switching times make this POWER MOS transistor ideal for high speed switching applications.

Typical applications include switching mode power supplies, uninterruptible power supplies and motor speed control.



### INTERNAL SCHEMATIC DIAGRAM



### ABSOLUTE MAXIMUM RATINGS

V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	500	V
V <sub>DGR</sub>	Drain-gate voltage (R <sub>GS</sub> = 20 KΩ)	500	V
V <sub>GS</sub>	Gate-source voltage	±20	V
I <sub>D</sub>	Drain current (continuous) T <sub>c</sub> = 25°C	9.5	A
I <sub>DM</sub>	Drain current (pulsed)	38	A
P <sub>tot</sub>	Total dissipation at T <sub>c</sub> < 25°C	125	W
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
T <sub>j</sub>	Max. operating junction temperature	150	°C
	DIN humidity category (DIN 40040)	E	
	IEC climatic category (DIN IEC 68-1)	55/150/56	

**THERMAL DATA**

$R_{thj - case}$	Thermal resistance junction-case	max	1.0	°C/W
$R_{thj - amb}$	Thermal resistance junction-ambient	max	45	°C/W

**ELECTRICAL CHARACTERISTICS** ( $T_j = 25^\circ\text{C}$  unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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**OFF**

$V_{(BR) DSS}$	Drain-source breakdown voltage	$I_D = 250 \mu\text{A}$	$V_{GS} = 0$	500		V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating}$	$T_j = 125^\circ\text{C}$		250 1000	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA

**ON**

$V_{GS (th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 1 \text{ mA}$	2.1	4	V
$R_{DS (on)}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}$	$I_D = 5.5 \text{ A}$		0.6	$\Omega$

**DYNAMIC**

$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}$	$I_D = 5.5 \text{ A}$	2.7		mho
$C_{iss}$	Input capacitance	$V_{DS} = 25 \text{ V}$ $V_{GS} = 0$	$f = 1 \text{ MHz}$		4900	pF
$C_{oss}$	Output capacitance				400	pF
$C_{rss}$	Reverse transfer capacitance				170	pF

**SWITCHING**

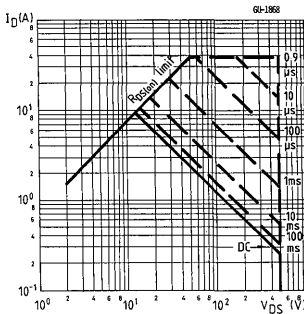
$t_d (on)$	Turn-on time	$V_{DD} = 30 \text{ V}$ $R_{GS} = 50 \Omega$	$I_D = 2.8 \text{ A}$ $V_{GS} = 10 \text{ V}$		75	ns
$t_r$	Rise time				120	ns
$t_d (off)$	Turn-off delay time				430	ns
$t_f$	Fall time				140	ns

ELECTRICAL CHARACTERISTICS (Continued)

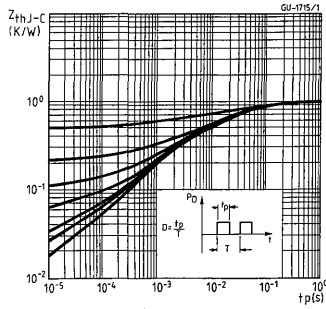
Parameters	Test Conditions	Min.	Typ.	Max.	Unit
$I_{SD}$ $I_{SDM}$	Source-drain current Source-drain current (pulsed)	$T_c = 25^\circ\text{C}$		9.5 38	A A
$V_{SD}$	Forward on voltage	$I_{SD} = 19\text{ A}$	$V_{GS} = 0$	1.7	V
$t_{rr}$	Reverse recovery time			1200	ns
$Q_{rr}$	Reverse recovered charge	$I_{SD} = 9.5\text{ A}$	$di/dt = 100\text{ A}/\mu\text{s}$	12	$\mu\text{C}$

SOURCE DRAIN DIODE

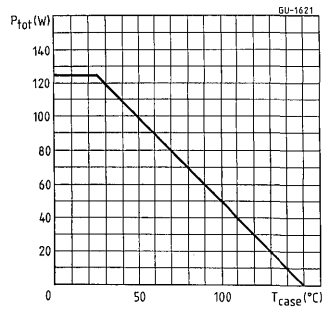
Safe operating areas



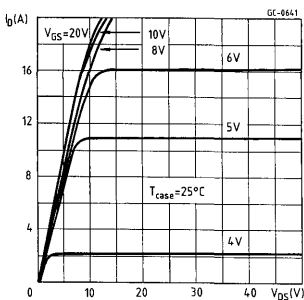
Thermal impedance



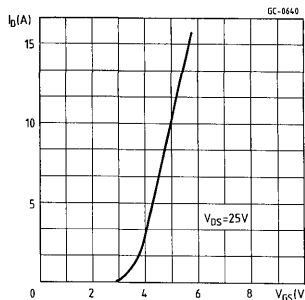
Derating curve



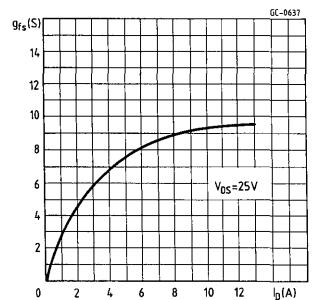
Output characteristics



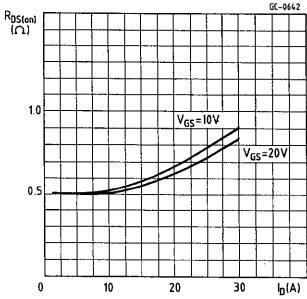
Transfer characteristics



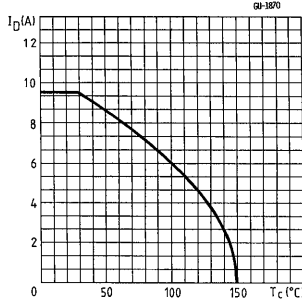
Transconductance



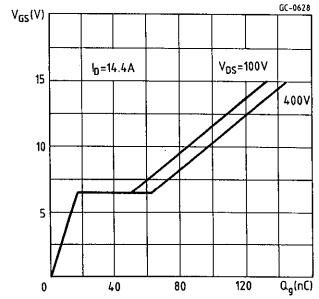
**Static drain-source on resistance**



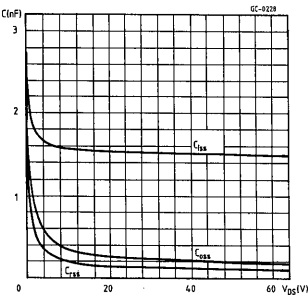
**Maximum drain current vs temperature**



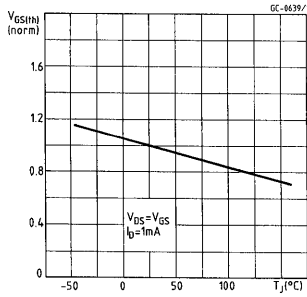
**Gate charge vs gate-source voltage**



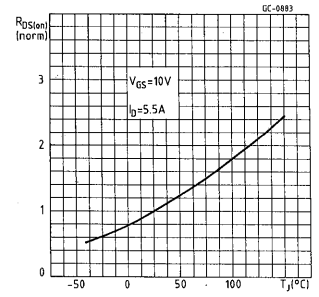
**Capacitance variation**



**Gate threshold voltage vs temperature**



**Drain-source on resistance vs temperature**



**Source-drain diode forward characteristics**

